

Pictures for public report

Logo

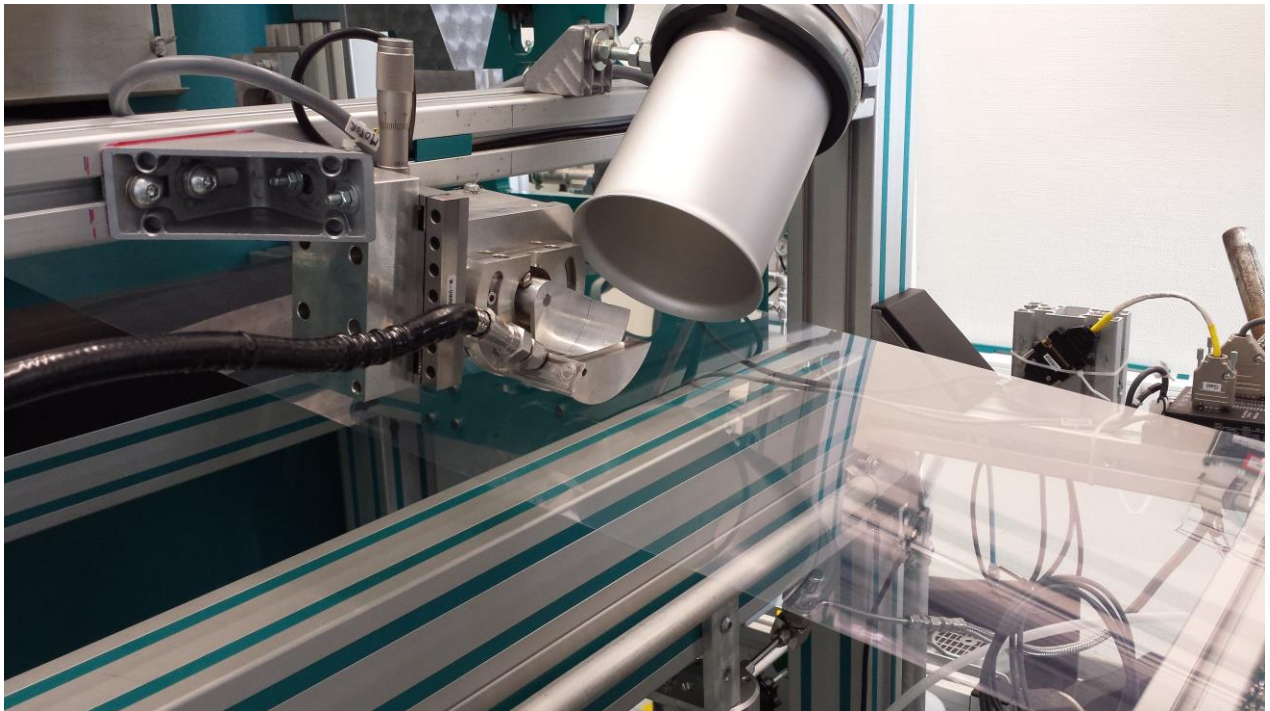


Clean4Yield econference

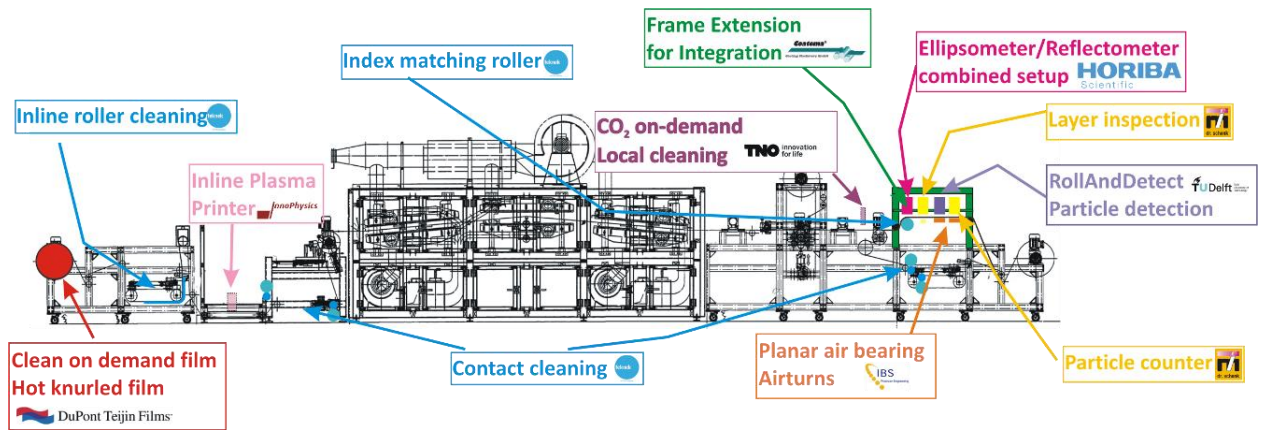
<http://plasticphotovoltaics.org/c4y/econference.html>

By TNO

LCU in R2R line



Integration at Holst Centre



By coatema

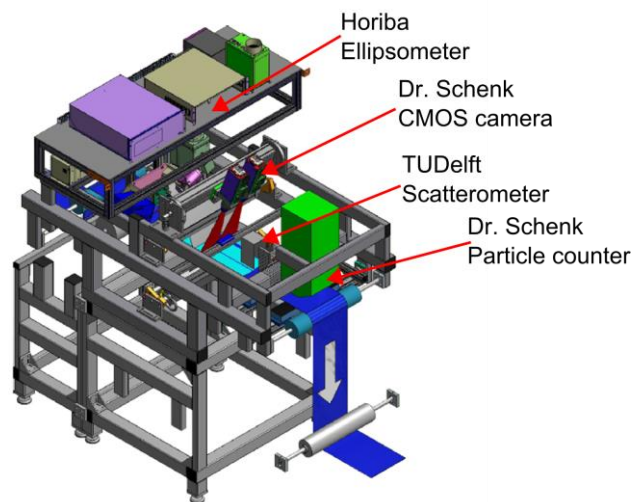


Figure x: Overview of the locations of the different optical inspection systems on the newly designed frame for the Holst Centre coating line.

To enable full functionality of the novel metrologies and to reduce film damage and particle generation Coatema integrated novel components like IBS Air turns and IBS air table into the integration frame (see figure X).

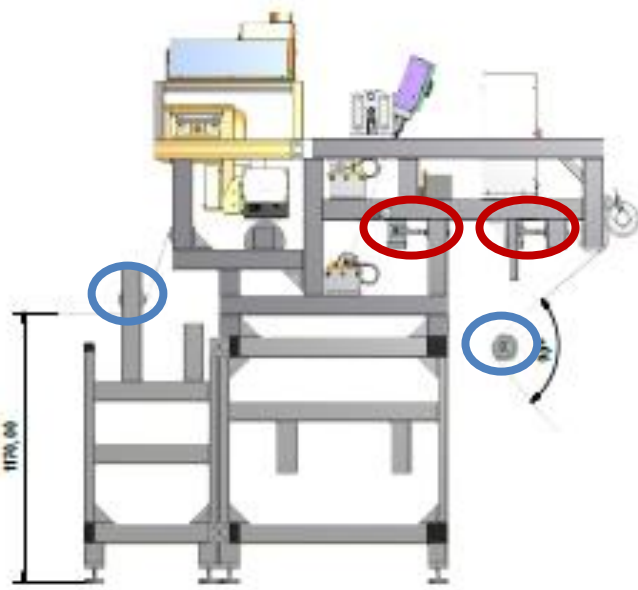
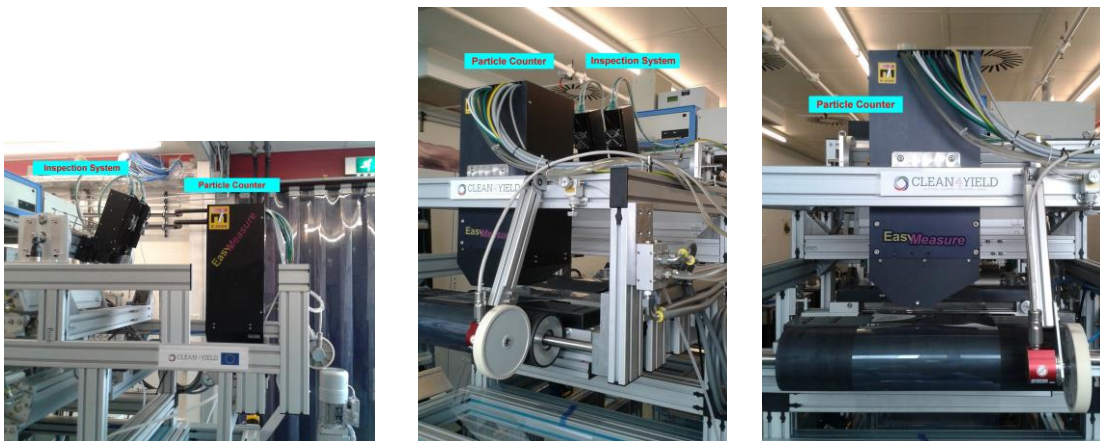


Figure X Location of IBS air turns and air tables in newly designed frame for Holst Centre

By Dr. Schenk

- 1 Integration of Inspection System and Particle Counter in the TNO line (AOI & PAC)
- 2 Integration of Inspection System and Particle Counter in the TNO line (Encoder)
- 3 Particle Counter integrated in the TNO line (PAC view1)



By Riso DTU

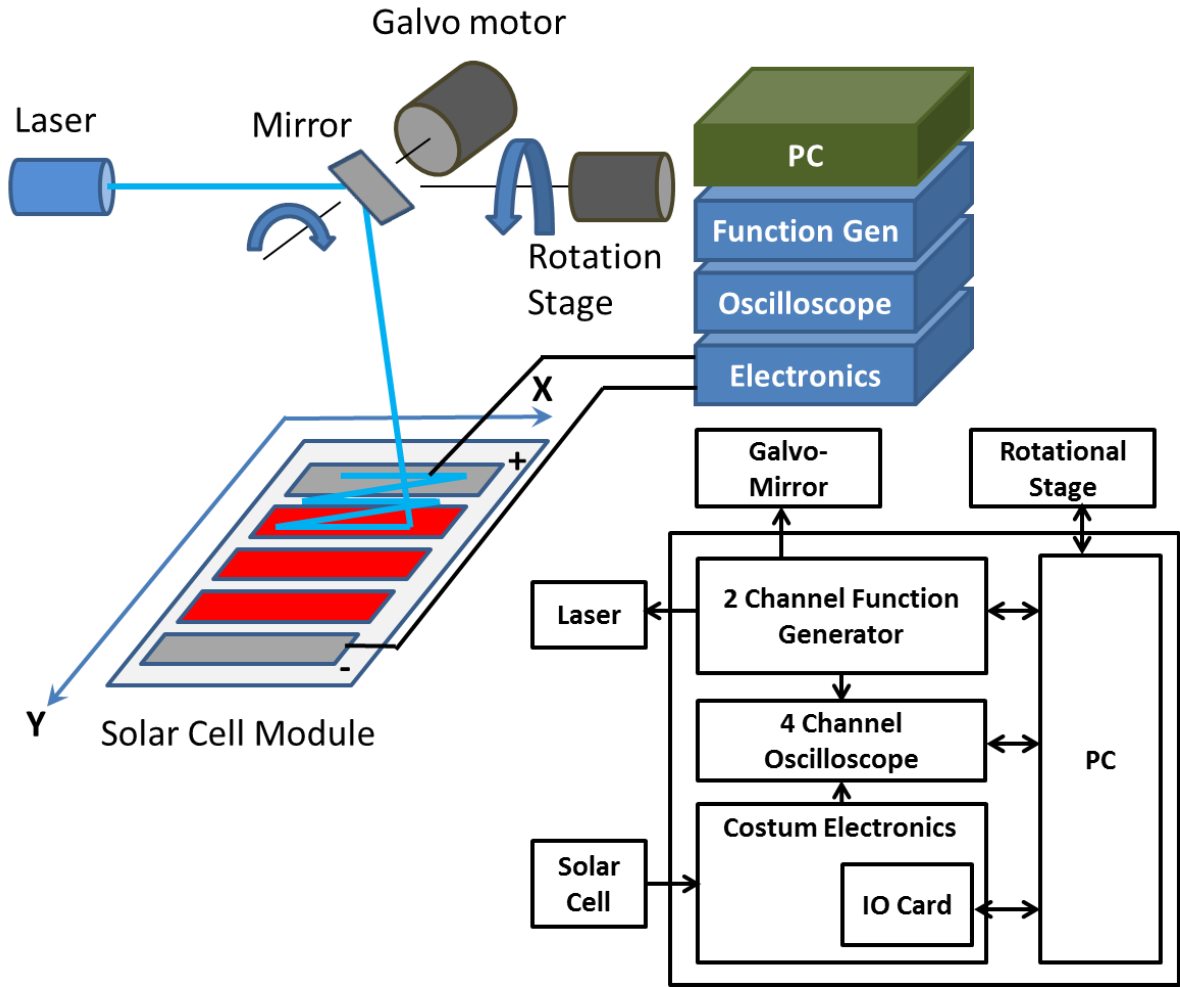


Figure 1. Schematic drawing of LBIC setup developed during the C4Y project.



Figure 2. Photograph of the LBIC setup integrated in a R2R line.

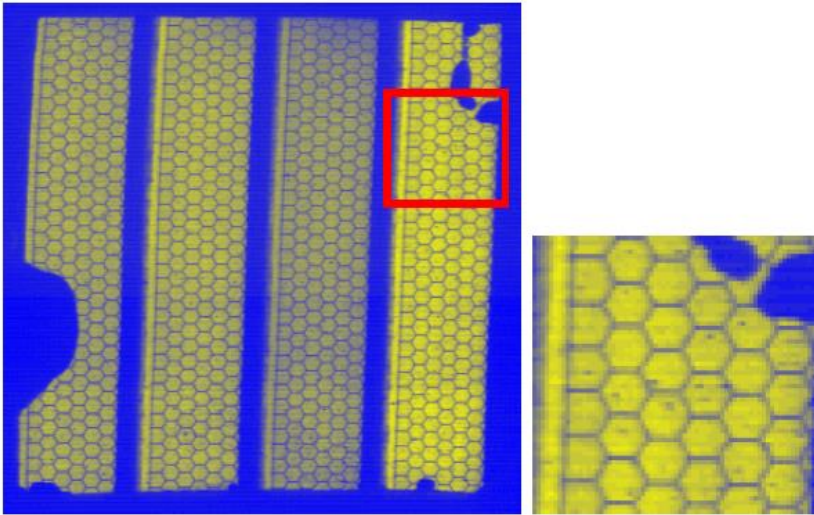


Figure 3. Photo and LBIC image of an OPV cell.

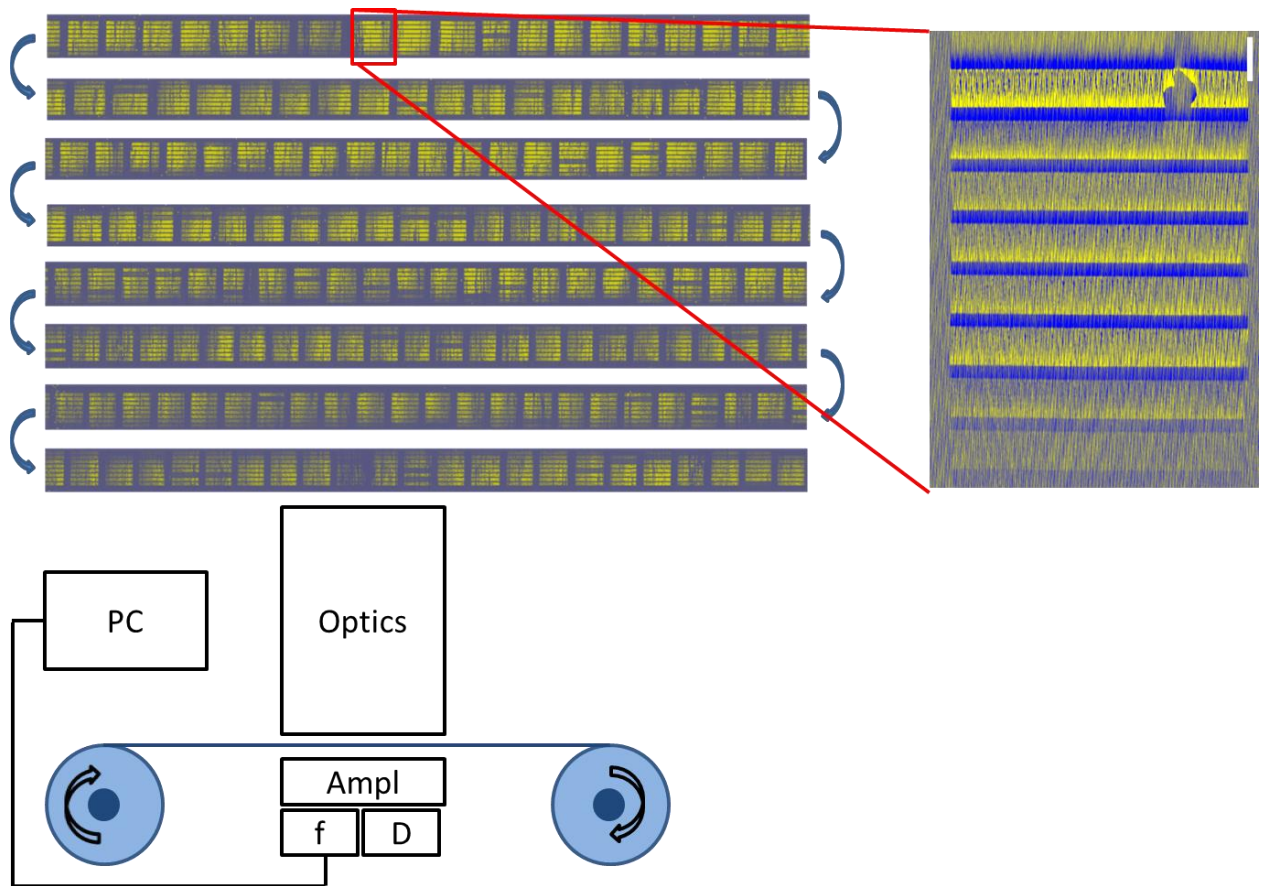


Figure 4. Diagram of the R2R LBIC instrument developed during C4Y and R2R LBIC imaging of a roll of OPV.

Best technical development IDtechEx award for DTF:

<http://www.idtechex.com/research/articles/idtechex-printed-electronics-europe-2015-award-winners-00007758.asp?donotredirect=true>

Publication of DTF with C4Yresults: <http://iconnect007.uberflip.com/i/324117-pcb-june2014/11>

By Horiba

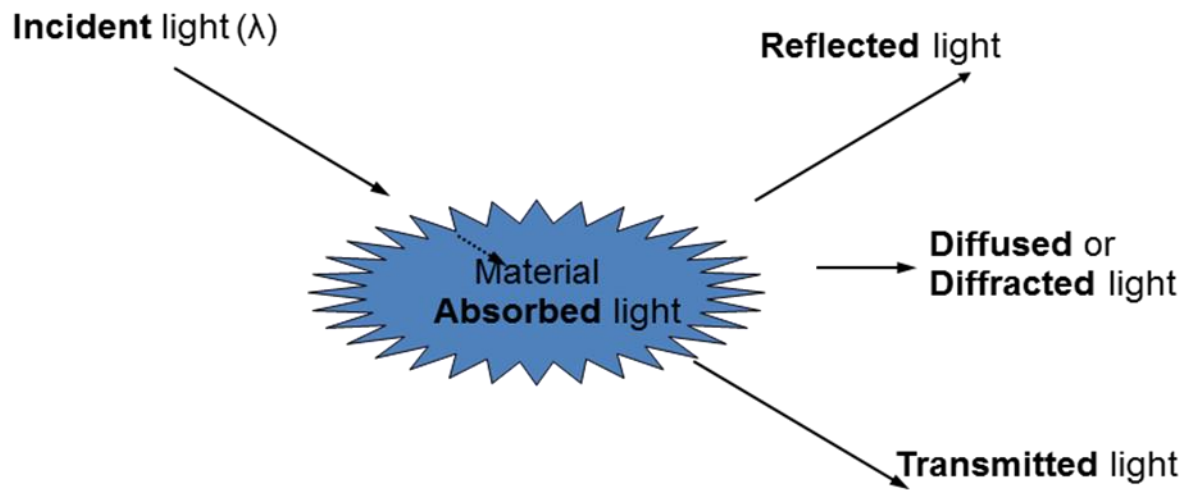


Figure 1 : Several Light-Material interactions exist

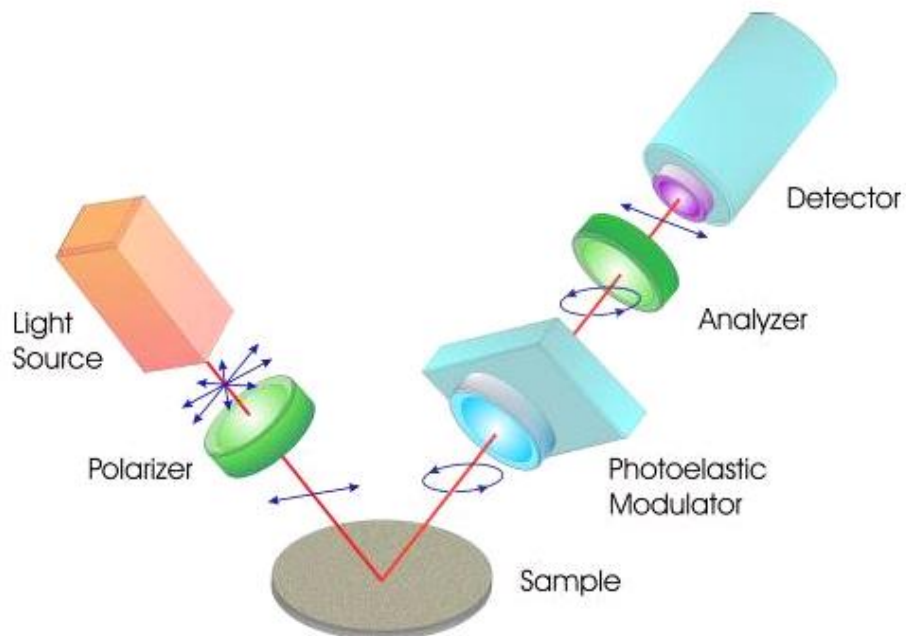


Figure 2 : Ellipsometry setup, a polarized light reflexion technique

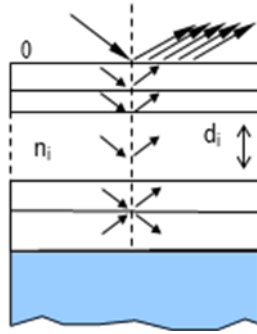


Figure 3 : Analyzing light reflected in a multilayered structure reveals thicknesses and optical properties

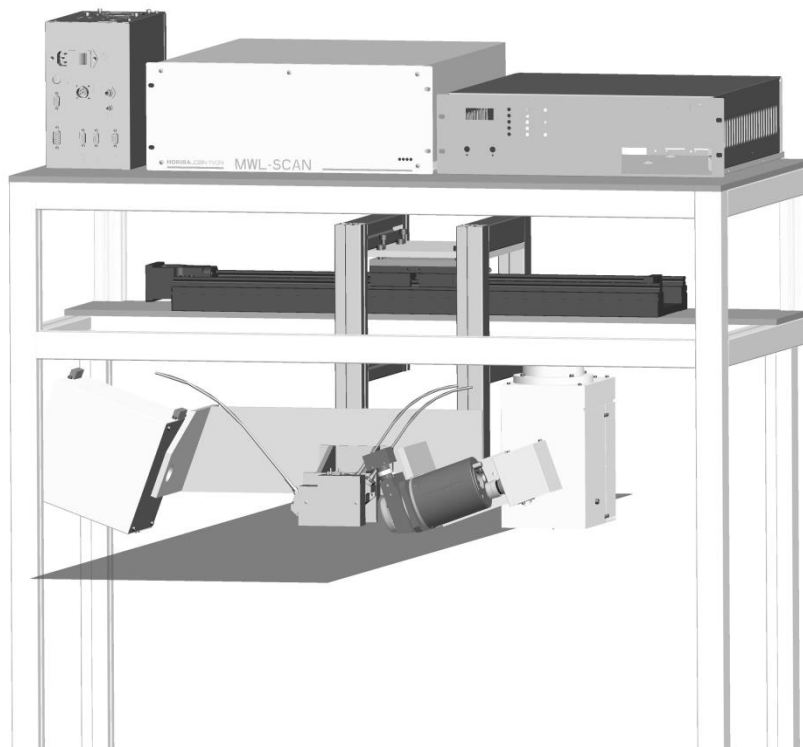


Figure 4 : Design of the Clean4Yield inline ellipsometer prototype

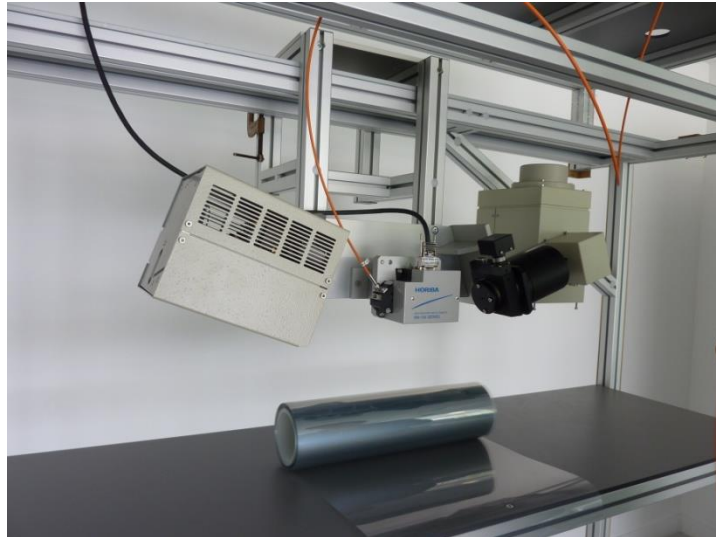


Figure 5 : Realisation of the prototype

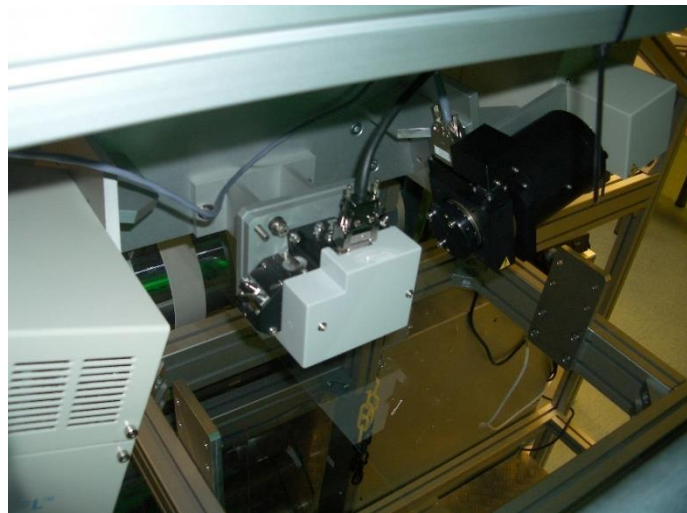


Figure 6 : Integration of the prototype inline

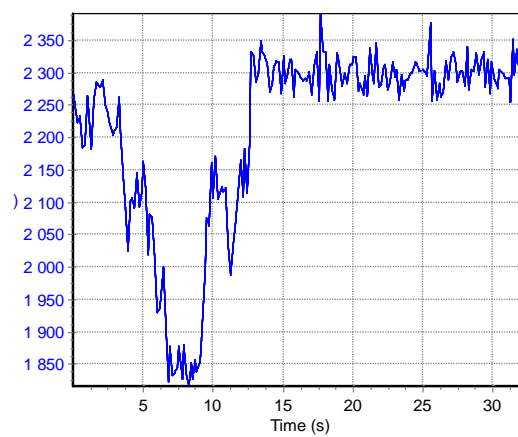
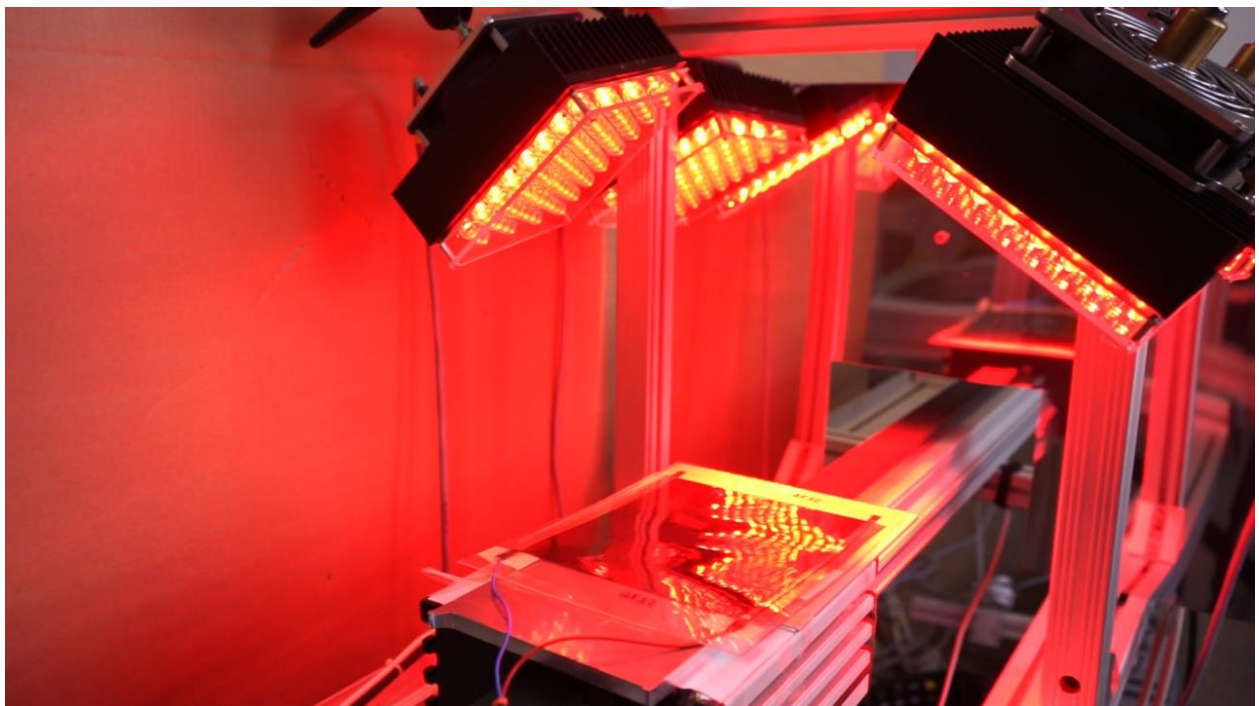
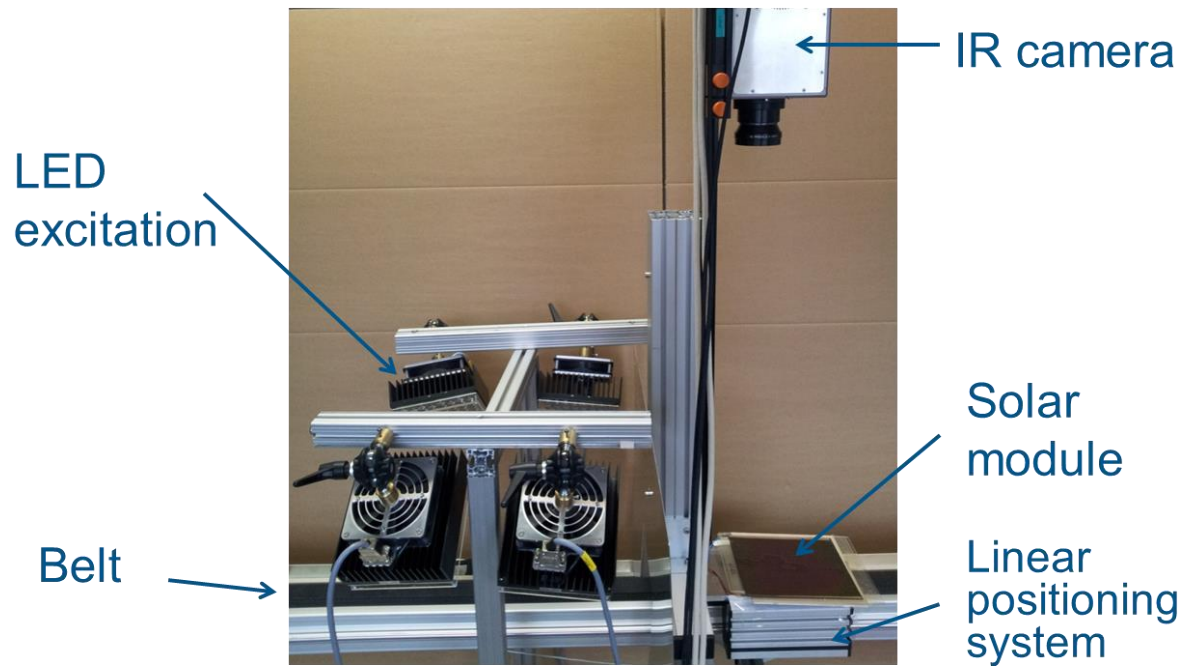


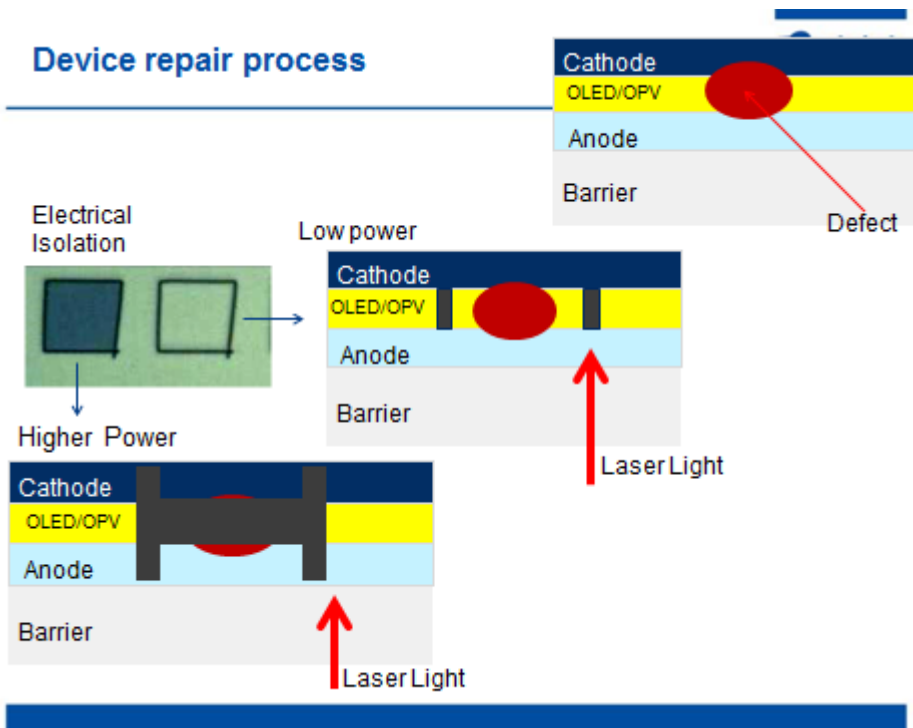
Figure 7 : Example of thickness variation detected on a moving sample

Philips: Olide images for use in the report can be found under www.lumibalde-experience.com/journalistsGB

DCG



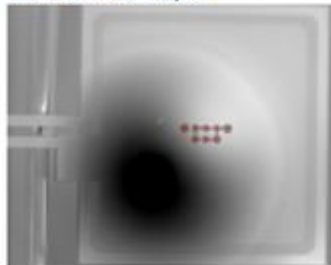
Device repair process



OPV Device repair: Defect location and ablation



Before laser repair



After laser repair

